

AFM and SEM investigations of ion beam synthesized Mg₂Si precipitates in Si substrates

Angelov, Christo; **Mikli, Valdek**; Amov, Blagoj; Goranova, E. Journal of optoelectronics and advanced materials 2005 / 1, p. 369-373
https://old.joam.inoe.ro/arhiva/pdf7_1/Angelov3.pdf

BSCCO ceramics doped with ferromagnetic manganite phases

Staneva, Anna; Stoyanova-Ivanova, Angelina; **Terzieva, Stanimira**; Shoumarova, Janna; Grigorov, K.; Zaleski, Andrzej; **Mikli, Valdek**; Angelov, Christo; Dimitriev, Yanko Journal of optoelectronics and advanced materials 2009 / 10, p. 1541-1544
https://www.researchgate.net/publication/279900785_BSCCO_ceramics_doped_with_ferromagnetic_manganite_phases

Comparative ellipsometric and ion beam analytical studies on ion beam crystallized silicon implanted with Zn and Pb ions

Lohner, Tivador; Angelov, Christo; **Mikli, Valdek** Thin solid films 2008 / 22, p. 8009-8012
<https://www.sciencedirect.com/science/article/pii/S0040609008003660>

Morphology of Y₁Ba₂Cu₃O_z and Y_{0.7}Ba₂Cu₃O_z bulk samples depending on Ca-substitution

Terzieva, Stanimira; Stoyanova-Ivanova, Angelina; Zalamova, K.; **Mikli, Valdek**; Angelov, Christo; Kovachev, V. Journal of optoelectronics and advanced materials 2005 / 1, p. 477-480
https://old.joam.inoe.ro/arhiva/pdf7_1/Terzieva.pdf

Pb and Bi nanocluster precipitation in high-dose implanted and RTA Si: SEM and RHEED analyses

Angelov, Christo; **Mikli, Valdek**; Kalitzova, M.; Beshkov, G. Proceedings of 11th Conference "Materials for Information Tech. in the New Millenium" : ISCMP : Varna, 2001 2001 / p. 452-455

Raman scattering characterization of ion-beam synthesized Mg₂Si. 1. Influence of the technological conditions on the formation of the Mg₂Si in(100) Si matrix

Atanassov, Alexander; Zlateva, Genoveva; Baleva, Mitra; Goranova, Ekaterina; Amov, Blagoj; Angelov, Christo; **Mikli, Valdek** Plasma processes and polymers 2006 / 2, p. 219-223 : ill
<https://onlinelibrary.wiley.com/doi/pdf/10.1002/ppap.200500088>

Solid phase and ion beam epitaxial crystallization of Si implanted with Zn and Pb ions

Angelov, Christo; Georgiev, S.; Amov, Blagoj; **Mikli, Valdek**; Lohner, Tivador Journal of optoelectronics and advanced materials 2007 / 2, p. 311-314
https://www.researchgate.net/publication/289467840_Solid_phase_and_ion_beam_epitaxial_crystallization_of_Si_implanted_with_Zn_and_Pb_ion_s

Structural investigations of ion beam synthesized [beeta]-FeSi₂

Angelov, Christo; Amov, Blagoj; **Mikli, Valdek**; Traksmas, Rainer Journal of optoelectronics and advanced materials 2009 / 10, p. 1490-1493
https://www.researchgate.net/publication/286966891_Structural_investigations_of_ion_beam_synthesized_b-FeSi2

Study of ion implanted Fe depth distribution in Si after pulsed ion beam treatment

Angelov, Christo; Georgiev, S.; Amov, Blagoj; Goranova, E.; **Mikli, Valdek**; Dezs, I.; Kotai, E. Journal of optoelectronics and advanced materials 2007 / 2, p. 307-310
https://www.researchgate.net/publication/289186791_Study_of_the_ion_implanted_Fe_depth_distribution_in_Si_after_pulsed_ion_beam_treatment

The influence of the partial Ca substitution on the microstructure of YBCO tapes

Terzieva, Stanimira; Stoyanova-Ivanova, Angelina; **Mikli, Valdek**; Zahariev, A.; Angelov, Christo; Dimitriev, Yanko; Kovachev, V. Journal of optoelectronics and advanced materials 2007 / 2, p. 453-455
https://www.researchgate.net/publication/286222792_The_influence_of_the_partial_Ca_substitution_on_the_microstructure_of_YBCO_tapes

Use of atomic-force microscopy for characterization of silicon, implated with heavy ions at high doses

Angelov, Christo; Groudev, P.; **Mikli, Valdek** Proceedings of 11th Conference "Materials for Information Tech. in the New Millenium" : ISCMP : Varna, 2001 2001 / p. 460-464